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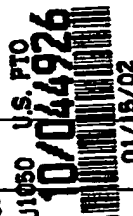
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Assigned**INFORMATION DISCLOSURE STATEMENT**

(Use several sheets if necessary)

Applicant: Shunpei YAMAZAKI et al.

Filing Date: January 15, 2002

Group: 2813

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
	5,648,277	07/15/1997	Zhang et al.			
	5,643,826	07/01/1997	Ohtani et al.			
	6,124,154	09/26/2000	Miyasaka			
	5,550,070	08/27/1996	Funai et al.			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation Yes N
	08-078329	03/22/1996	Japan			Abstract
	07-321339	12/08/1995	Japan			Abstract
	07-130652	05/19/1995	Japan			Abstract
	07-135318	05/23/1995	Japan			Abstract
	05-109737	04/30/1993	Japan			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	R. Shimokawa and Y. Hayashi, "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics, Vol. 27, No. 5, May, 1988, pp. 751-758

Examiner

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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.